## Notice of References Cited Application/Control No. 10/551,436 Examiner Nhon T. Diep Applicant(s)/Patent Under Reexamination AVNI ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,600,517	07-2003	He et al.	348/625
*	В	US-6,184,922	02-2001	Saito et al.	348/65
*	С	US-6,501,862	12-2002	Fukuhara et al.	382/249
*	D	US-6,661,463	12-2003	Geshwind, David Michael	348/384.1
*	E	US-6,492,982	12-2002	Matsuzaki et al.	345/204
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
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## **NON-PATENT DOCUMENTS**

	NOTE ATENT DOCUMENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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